Attorney Docket: 361007-000025



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: Herr, Daniel Joseph Christian

Group Art Unit: 2811

Serial Number: 10/604,747

Examiner: Unassigned

Filed: August 14, 2003

For: DETERMINISTICALLY DOPED FIELD-EFFECT DEVICES AND METHODS OF MAKING SAME

Commissioner for Patents PO Box 1450 Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT <u>UNDER 37 C.F.R. § 1.56 AND 37 C.F.R. § 1.97</u>

It is respectfully requested that the document listed on the attached Form PTO/SB/08A be considered by the Patent and Trademark Office in the above-referenced application and made of record therein. A full text copy of the relevant documents are enclosed. This information disclosure statement submitted herewith is being filed within three months of the filing date of the application or date of entry into the national stage of an international application or before the mailing date of a first Office action on the merits, whichever event occurs last.

Respectfully submitted,

By:

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919-286-8000 Phone: Facsimile: 919-286-8199 December 16, 2003

Date

CERTIFICATE OF MAILING

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PTO/SB/08a (08-03)

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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

C mplete if Known Application Number 10/604,747 Filing Date August 14, 2003 First Named Inventor Herr, Daniel J seph Christian Art Unit **Examiner Name**

(use as many sheets as necessary) 361007-000025 Sheet Attorney Docket Number

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Examiner Initials'	Cite No.1	Document Number Number-Kind Code ² (if known	MM-Di	tion Date D-YYYY		ame of Patentee or cant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant			
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TRADEMAR		NON PATEN	IT LITERATURE DOCUMEN	TS						
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.								
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